PERFORMANCE CHECKSHEET

Model: AVR-EB4-B
Type: Semiconductor Device Tester
S.N.: 13256
Date: January 20, 2015

Basic specifications: →

Test Waveforms

With an On Semi 1N4937 (date code 1338) installed in the AVX-TRR-MIX test jig, connected using the 60 cm / 24" coaxial cable:

$I_F = +2A, I_R = -4A, I_{RR} = -1A.$

100 Hz, 20 us PW.

5V (1A) / div, 40 ns/div.

Measured $t_{RR} = 118$ ns.

With a generic 1N4004 installed in the AVX-TRR-MIX test jig, connected using the 60 cm / 24" coaxial cable:

$I_F = +2A, I_R = -4A, I_{RR} = -1A.$

100 Hz, 20 us PW.

5V (1A) / div, 400 ns/div.

Measured $t_{RR} = 1.29$ us.
Mainframe output, with a zero Ohm jumper installed in the AVX-TRR-MIX test jig:

50 V / div, 20 ns/div. +100V, -200V.

10% - 90% fall time shown.